

AN8212K

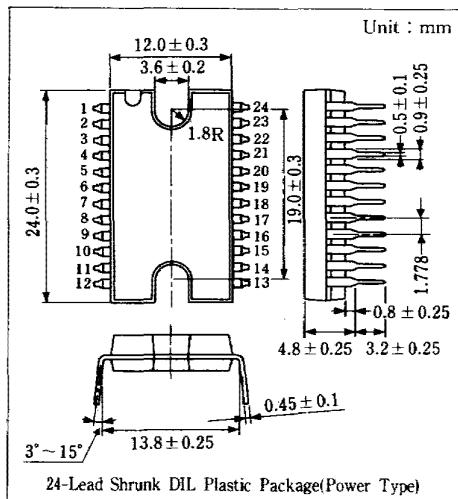
IC for FDD Spindle Motor Control

■ Outline

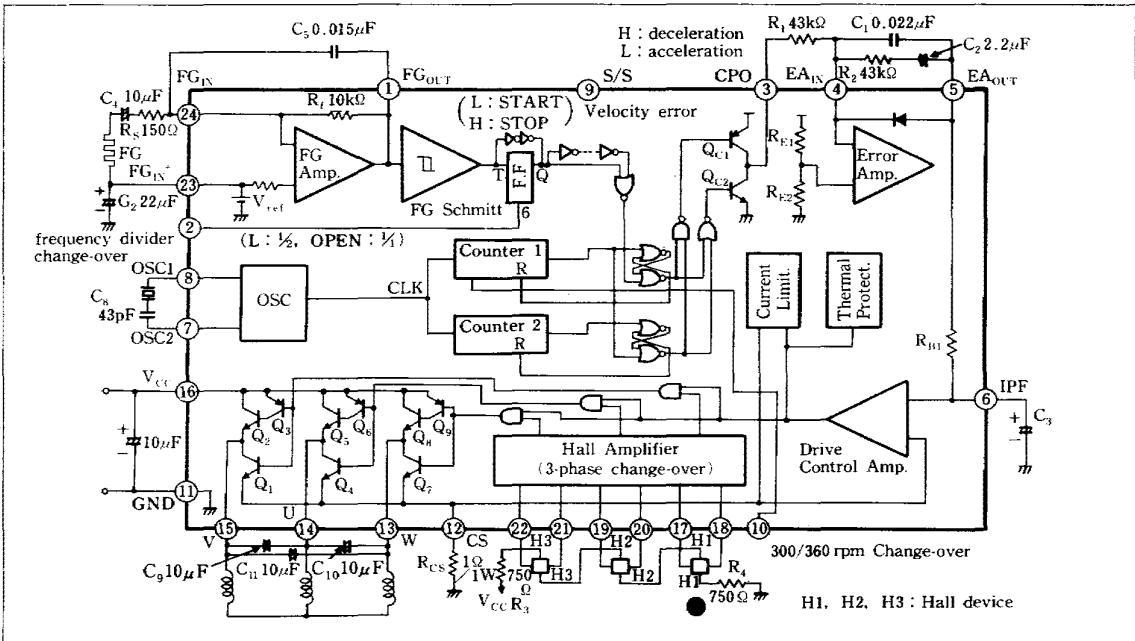
The AN8212K is an integrated circuit in which 300/360 rpm speed change-over function is added to the AN8210NK for FDD spindle motor.

■ Features

- Speed change-over built-in (300/360rpm)
- FG divider change-over built-in (1/2)
- Speed control by digital velocity detector
- 3-phase full wave current drive
- Motor current limit built-in
- Thermal protect built-in
- Start/stop switch



■ Block Diagram and Application Circuit



■ Pin

Pin No.	Pin Name	Pin No.	Pin Name
1	FG Amp. Output	13	Motor Drive Output W
2	FG Divider	14	Motor Drive Output U
3	Verocity Error Output	15	Motor Drive Output V
4	Error Amp. Inversion Input	16	V _{cc}
5	Error Amp. Output	17	Hall Amp. 1+ Input
6	Low-Pass Filter	18	Hall Amp. 1- Input
7	Oscillation Circuit 2	19	Hall Amp. 2+ Input
8	Oscillaton Circuit 1	20	Hall Amp. 2- Input
9	Start/Stop Switching	21	Hall Amp. 3- Input
10	300/360 rpm Switching	22	Hall Amp. 3+ Input
11	GND	23	FG Amp.+Input
12	Current Sensing	24	FG Amp.+Input

■ Absolute Maximum Ratings (Ta=25°C)

Item	Symbol	Rating	Unit
Supply Voltage	V _{cc}	20	V
Motor Drive Pin Voltage	V ₁₃ ,V ₁₄ ,V ₁₅	20	V
Pin Applied Voltage 1	V ₁ ~V ₉ ,V ₂₄	-0.3~+5.5	V
Pin Applied Voltage 2	V ₁₇ ~V ₂₂	0~V _{cc}	V
Pin Applied Voltage 3	V ₁₀	-0.3~0.9	V
Supply Current	I _{cc}	900	mA
Pin Current 1	I ₁₂	-900~0	mA
Motor Drive Pin Current	I ₁₃ ,I ₁₄ ,I ₁₅	-900~+900	mA
Pin Current 2	I ₂₃	-20~+1	mA
Power Dissipation	P _D	2.5	W
Operating Ambient Temperature	T _{opr}	-20~+75	°C
Storage Temperature	T _{stg}	-55~+150	°C

■ Electrical Characteristics (V_{cc}=12V, Ta=25°C)

Item	Symbol	Test Circuit	Condition	min.	typ.	max.	Unit
Standby Quiescent Current	I _{QS}	1	V _{S/S} =2V		0.3	0.5	mA
No-load Quiescent Current	I _{QN}	1	V _{S/S} =0V		18	25	mA
Reference Voltage Part							
Reference Voltage	V _{OR}	2	I _{OR} =0mA	2.3		2.8	V
Output Sink Current	I _{OR+}	2		0.5			mA
Output Source Current	I _{OR-}	2			-15	-10	mA
Output Impedance	Z _{OR}	2	I _{OR} =0~ -10mA		5	10	Ω
FG Amp./Schmitt Part							
Offset Voltage	V _{OSF}	3		-15		15	mV
Feedback Resistance	R _{FF}			6.2	8.7	11.2	kΩ
Output Sink Current	I _{OF+}	4	V _S =0V, V _R =3V	3			mA
Output Source Current	I _{OF-}	4	V _S =0V, V _R =2V			-3	mA
Speed Error Detect Part (Logic)							
Count Switch-Over Voltage	V _{CT}	5		1.0	1.8	2.5	V
Count No. 1	N _{C11}	5	V _{CT} =L		1006		Time
Count No. 2	N _{C12}	5	V _{CT} =H		838		Time

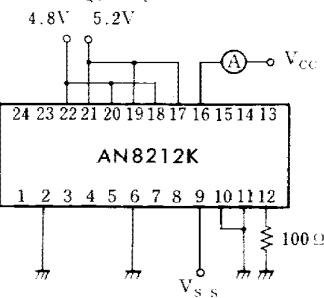
■ Electrical Characteristics (Cont'd) ($V_{cc}=12V$, $Ta=25^{\circ}C$)

Item	Symbol	Test Circuit	Condition	min.	typ.	max.	Unit
Speed Error Output Part							
Output Low Voltage	V_{OLC}	6			0.1	0.3	V
Output High Voltage	V_{OHC}	6		4.4		5.2	V
Output Sink Current	I_{OC^+}	6		300			μA
Output Source Current	I_{OC^-}	6				-150	μA
Error Amp. Part							
Output Sink Current	I_{OE^+}	8		2			mA
Output Source Current	I_{OE^-}	8				-2	mA
Gain Bandwidth Product	f_{GBE}	8		500			kHz
FG Divider Change-Over			$V_{FG}=0V$	600/720			rpm
300/360 rpm Change-Over			$V_{FG}=2.5V$	300/360			rpm
Drive Control Amp. Part							
Threshold Voltage	V_{THD}	9		2.3	2.55	2.8	V
Drive Gain	A_{CD}	9		1.6	1.8	2.0	Time
Limiter Voltage	V_{LD}	9		0.59	0.66	0.72	V
Open Loop Drive Gain	A_{OD}			30	30		dB
Hall Amp. Part							
Phase Input Voltage Range	V_{ICH}			2		$V_{cc}-2$	V
Error Input Voltage Range	V_{IDH}					400	mV
Hall Input Sensitivity	V_{ISH}			10			mV
Hall Offset Voltage	V_{OSH}	10				20	mV
Input Bias Current	I_{BH}	11		1.0	5.0		μA
Drive Output Part							
Saturation Voltage(on V_{cc})	V_{SU}	12				1.4	V
Saturation Voltage (on ground)	V_{SL}	12				1.1	V
OFF Leak Current	I_{LO}	12		-20		20	μA
Start/Stop Control Part							
Input Low Voltage	V_{IL}		$V_{S/S}=0V$			0.7	V
Input High Voltage	V_{IH}		$V_{S/S}=2V$	2			V
Input Low Current	I_{IL}	13		-100	-50		μA
Input High Current	I_{IH}	13			10	100	μA
Speed Error Output Part							
Output Leak Current	I_{LC^*}	6				0.1	μA
Input Bias Current	I_{BE^*}	7				0.1	μA
Quiescent Breakdown Level	V_s^*		Applied between GND and each pin ($C=100pF$, No R)	300			V

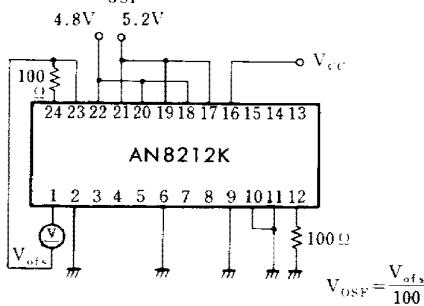
Note) Operating Supply Voltage Range : $V_{CC(\text{ope})}=9\sim16V$

* These values are of reference values but not guaranteed values.

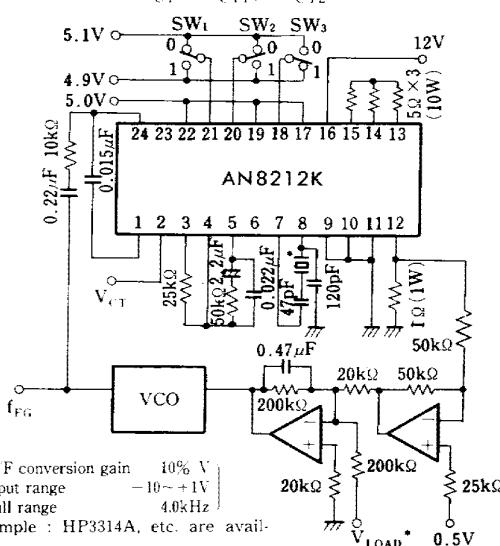
Test Circuit 1 (I_{QS} , I_{QX})



Test Circuit 3 (V_{0SE})



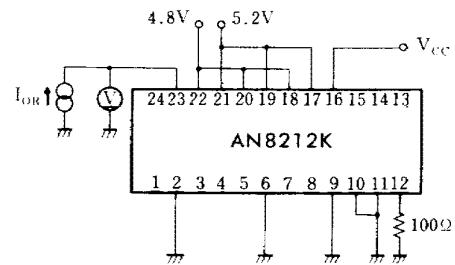
Test Circuit 5 (V_{CE} , N_{CT1} , N_{CT2})



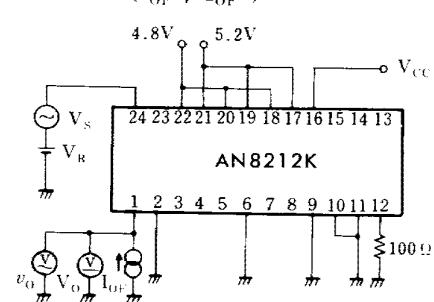
V/F conversion gain 10% V
 Input range -10~+1V
 Full range 4.0kHz
 Example : HP3314A, etc. are avail-

*Ceramic resonator (512kHz)

Test Circuit 2 (V_{QB} , I_{QB}^+ , I_{QB}^- , Z_{QB})

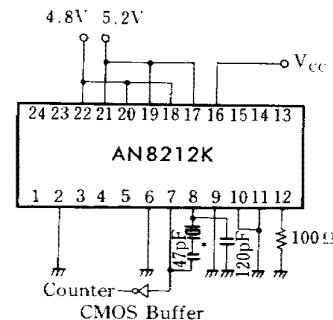


Test Circuit 4 (I_{OE^+} , I_{OE^-})



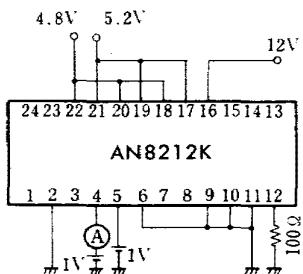
When output sink current $I_{OF} = 3\text{mA}$, $V_O < 1.7\text{V}$ ($V_R = 3\text{V}$, $V_S = 0\text{V}$)
 When output source current $I_{OF} = -3\text{mA}$, $V_O > 3.2\text{V}$, ($V_R = 2\text{V}$, $V_S = 0\text{V}$)
 Open loop gain $A_{VF} = 20 \log \left(\frac{\nu_O}{V_S} \right)$

Test Circuit 6 (V_{OLC} , V_{OHC} , I_{OC^+} , I_{OC^-} , I_{BE})

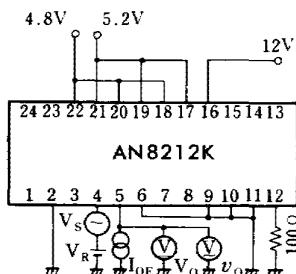


*Ceramic resonator is used (512kHz)

Test Circuit 7 (I_{BE})

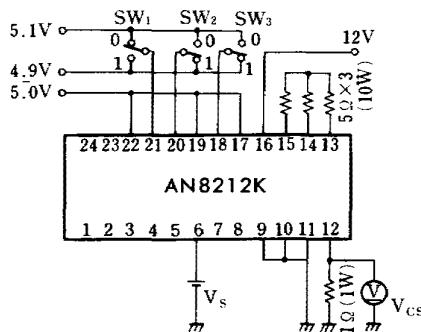


Test Circuit 8 (I_{QE}^+ , I_{QE}^- , f_{GBE})

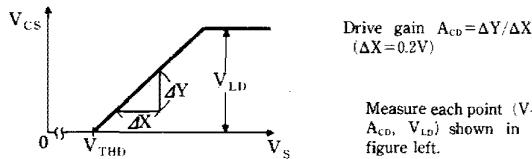


When output sink current $I_{O^+} = 2\text{mA}$, $V_o < 1.6\text{V}$ ($V_R = 3\text{V}$, $V_S = 0\text{V}$)
 When output source current $I_{O^-} = -2\text{mA}$, $V_o > 1.8\text{V}$, ($V_R = 2\text{V}$, $V_S = 0\text{V}$)
 Open loop gain $A_{VF} = 20 \log \left(\frac{V_o}{V_S} \right)$

Test Circuit 9 (V_{THD} , A_{CP} , V_{LP})



$V_s - V_{CS}$ Input Characteristics

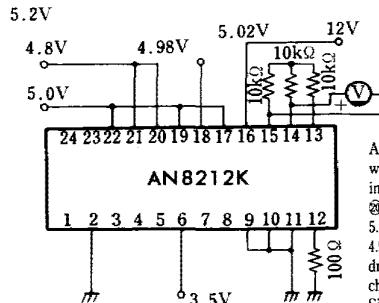


Measure each point (V_{THD} , A_{CD} , V_{LD}) shown in the figure left.

Test	SW ₁	SW ₂	SW ₃
1	1	0	1
2	1	1	0
3	0	1	1

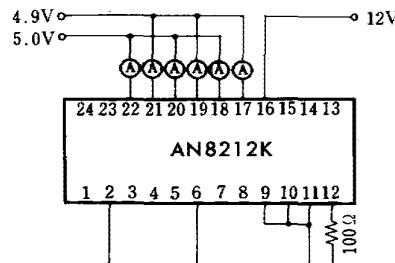
At the same time, change over SW₁ to SW₃, as shown in the figure left and measure each point every item above.

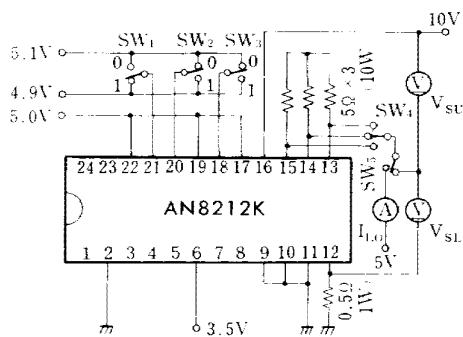
Test Circuit 10 ($V_{O\bar{S}H}$)



As shown in the figure left, when all polarity of hall amp. input is reversed such as Pin ② and ④ are reversed from 5.2V to 4.8V and Pin ③ from 4.98V to 5.02V, polarity of drive output is reversed, checking offset voltage Pin ⑩. Similarly, measurement is made for each phase.

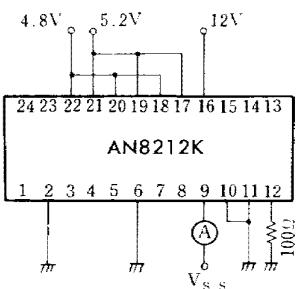
Test Circuit 11 (I_{BH})



Test Circuit 12 (V_{SU}, V_{SL}, I_{IO})**Logical Table of Phase Change-over Hall Input-Drive Output Logic**

No.	SW ₁	SW ₂	SW ₃	13(W)	14(U)	15(V)
1	1	1	1	off	off	off
2	1	1	0	off	H	L
3	1	0	1	H	L	off
4	0	1	1	L	off	H
5	1	0	0	H	off	L
6	0	1	0	L	H	off
7	0	0	1	off	L	H
8	0	0	0	off	off	off

According to the logic table above, determine the states of output Pins ⑩ to ⑫ and select SW₁ or SW₃ appropriately.

Test Circuit 13 (I_{II}, I_{IH})**P_D Ta**